THEORY OF MACHINE LEARNING

LECTURE 6

VC DIMENSION, FUNDAMENTAL THEOREM

LAST LECTURE

Corecet: strong coresets.

- Representative sample: for a hyp class H and distribution D over X, S is called "representative" if $\frac{\text{training error}}{\text{for all } h \in H, | \text{ (avg error on S)(h) risk_D (h) } | \leq \epsilon$, test error.
- Observation. If training data happened to be a representative sample, ERM gives a hypothesis with good generalization. (You will be close (Question of ERM being efficient is orthogonal...) to the periodical the best held.)
- Observation 2. For a finite hypothesis class, a random sample of size ~
 log |H| is representative
- Proof using "concentration" inequality (Chernoff/Hoeffding)

CONCENTRATION BOUND

• Chernoff bound (Hoeffding). Suppose $X_1, X_2, ... X_n$ are n iid samples from a distribution with mean μ and support [a, b]. Then we have

$$\Pr\left[\left|\frac{1}{n}\left(X_1 + \dots + X_n\right) - \mu\right| > \epsilon\right] \le 2\exp\left(-\frac{\epsilon^2 n}{(a-b)^2}\right)$$

Note: exponential dependence on n

ITE CLASSES ARE LEARNABLE

71: finite hyp. clas: $H = \{h_1, h_2, \ldots, h_m \}$.

- <u>Claim</u>: for any X and distribution D over it, a sample of size $O\left(\frac{1}{\epsilon^2}\log^{\frac{M}{2H}}\right)$ Jener on sample - enror on \ \le \\ \\

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 Night \ \prob \cdot 7, \le 1-8. is representative with prob. at least $1-\delta$
- Proof: write 'm' for the sample size
 - First look at a single $h \in H$

[0,1]

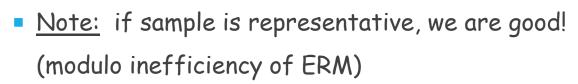
- Prob. that |sample error(h) risk(h)| > ϵ can be viewed as an application of Chernoff bound! $X_1 = \begin{cases} 1 & \text{if } h \text{ is incorrect on Sample #1} \\ 0 & \text{if } h \text{ is correct.} \end{cases}$
- Gives a bound $2e^{-\epsilon^2 m}$
- Union bound to prove that Pr[diff > ϵ for some h] < δ

@ - Let us say that S is "bad" for h "y Sample error on S(h) - risk (h) > E. Prob (S is bad for some given h) $\leq \frac{S}{1H}$ (when we sample)

a random S) => Prob(S is good for ALL hEH)> 1-8. A, B.
Prob(S is good for ALL hEH)> 1-8. Pr(Sigord + he3t) = 1-Pr(3heH s.t. Sis bad for h). = Pr(A)+Pr(B) Want to claim: Pr[] h∈ It s.t. S is bad for h] ≤ 8. ≤ Pr(A)+ Pr(B) Pr(Sisbad for h, VS is bad for h₂) V.... VS is bad for h_m)

E Pr(Sisbad for h₃) + Pr(Sis bad for h₂) + ... \leq S.

WHAT ABOUT INFINITE CLASSES?





Example of threshold functions on a line

If IXI is finite, then the fact that there are infinitely marry hypotheses not matter!

GROWTH FUNCTION OF A CLASS

Obsn: What matters isn't the # of distinct hypotheses, it's
the # of ways in which the hypotheses classify "points of
the domain.

Maximum number of "possible classifications" of an input of size m

Growth function: of a hypothesis class power domain X:

$$\gamma(m) := \max_{X \in X} \{ \text{ H of distinct ways in which } \} \\
\leq m \quad \text{SI = m } \text{ hypotheses in } \text{ H classify S } \text{ J} \\
\leq m \quad \text{SSX} \\
\text{t.} \quad \text{t.} \quad \text{two classifications are distinct } \text{ J} \\
\text{they differ on even one enample.} \\
+ \text{J t} \quad \text{S:} (x_1, x_2, \dots, x_m) \\
h(s) = (t, -, -, \dots) \rightarrow \text{Sign pattern}.$$

Qn: What is the growth function of LTFs, over X = R.

TH(m) = max

Sis classified by hypotheses in H

SSIR

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The state of the growth function of LTFs is the growth function of the grow $T_{H}(m) = m + 1.$ what is the growth function of intervals on the Rline? Simple exercise: $\gamma_{\mathcal{H}}(m) \leq O(m^2)$.

Consider $\mathcal{H} = \left\{ \text{conven polygons in } \mathbb{R}^2 \right\}.$ What is $(r_t(m))$? +++--To show $r_{\mathcal{H}}(m) = 2^m$, you must show one set of mpts S.I. all sign patterns on those points are possible. 1 (m) = 2 m

LEARNABILITY IN TERMS OF THE GROWTH FUNCTION

- finite hyp dasses: O(log HI) samples suffice for PAC-barrieg
- Theorem: Suppose $\tau_H(m)$ is an upper bound on the total number of distinct "classifications" (or "sign patterns") possible for any sample of size m. Then for any X, D, if we take a sample S of size m, we have, with prob. $1-\delta$,

$$\sup_{h \in H} |err(h,S) - err(h,D)| \le \frac{4 + \sqrt{\log \tau_H(2m)}}{\delta \sqrt{2m}}$$
how big should
$$\min_{h \in S} \sup_{h \in H} |err(h,S) - err(h,D)| \le \frac{4 + \sqrt{\log \tau_H(2m)}}{\delta \sqrt{2m}}$$

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HOW TO BOUND GROWTH FUNCTION?

• Shattering.

VC dimension.

SAUER-SHELAH LEMMA (VAPNIK-CHERVONENKIS)

• Lemma. Let H be a hypothesis class of finite VC dimension d. Then for every m, we have:

$$au_H(m) \leq {m \choose 0} + {m \choose 1} + \cdots + {m \choose d}$$

- Much better than exponential, for m large
- Proof by a clever inductive argument

FUNDAMENTAL THEOREM OF (STAT) LEARNING THEORY

- Theorem: The following statements are equivalent:
 - Class H is PAC learnable
 - Class H is agnostically PAC learnable
 - Class H has finite VC dimension

 Implies that if H has infinite VC dimension, it is <u>not</u> PAC learnable! (same proof as no-free-lunch theorem)

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OUTLINE -- THE TWO SAMPLE TRICK

- Want to show that a random sample is ϵ -representative
- Take sample S, define event:
 - A = Pr [sample is not representative]
- Way to "test" if S is not representative?
 - "Cross validation"
- Define new event S, S'
- "Swapping"